

Materials List for:

Cooling Rate Dependent Ellipsometry Measurements to Determine the Dynamics of Thin Glassy Films

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URL: <https://www.jove.com/video/53499>

DOI: [doi:10.3791/53499](https://doi.org/10.3791/53499)

Materials

Name	Company	Catalog Number	Comments
Toluene	Sigma Aldrich	179418-1L	This can be purchased from any chemical company.
Atactic Polystyrene	Polymer Source Inc.	P-4092-S	This can be purchased from any chemical company.
THMS 600 temperature stage	Linkam	THMS 600	any temperature stage that can be fit to an ellipsometer could be used.
M2000V Spectroscopic Ellipsometer	J.A. Woollam	M200V	This procedure should be applicable for any spectroscopic ellipsometer.
Spin Coater	Laurell Technologies	WS-650-23B	This Procedure is possible with any spin coater
Sample vials	Fisher Scientific	02-912-379	Any sample vials will do
Silicon wafers	Virginia semi conductors	325S1410694D	